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Customer No. 22,852 Attorney Docket No. 04329.2555

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re A	Application of:)
Hiroshi NOMURA) Group Art Unit: 2877
Application No.: 09/816,164) Examiner: G. Stock Jr.
Filed:	March 26, 2001)
For:	METHOD OF MEASURING DISPLACEMENT OF OPTICAL AXIS, OPTICAL MICROSCOPE AND EVALUATION MARK	
Commissioner for Patents Washington, DC 20231		
Sir:		

<u>AMENDMENT</u>

In reply to the Office Action dated March 28, 2003, the period for eply extending to June 30, 2003 (June 28, 2003 being a Saturday), please amend the application as follows:

IN THE ABSTRACT:

Please amend the Abstract as follows:

FINNEGAN HENDERSON FARABOW GARRETT & DUNNER LLP

1300 I Street, NW Washington, DC 20005 202.408.4000 Fax 202.408.4400 www.finnegan.com A method of measuring the displacement of the optical axis of an optical microscope having an illumination optical system and a projection optical system includes a step of irradiating the evaluation mark having diffraction grating patterns formed on a substrate with illumination light by way of the illumination optical system and observing the evaluation mark by way of the projection optical system to obtain the